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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/692,489	TAKU ET AL.	
Examiner	Art Unit	
Marlon T. Fletcher	2837	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
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SEE SEARC PRIN		2/1/2006	MTF

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	2/1/2006	MTF		
TEXT SEARCH UPDATE: SEE SEARCH HISTORY PRINTOUT	2/1/2006	MTF		
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